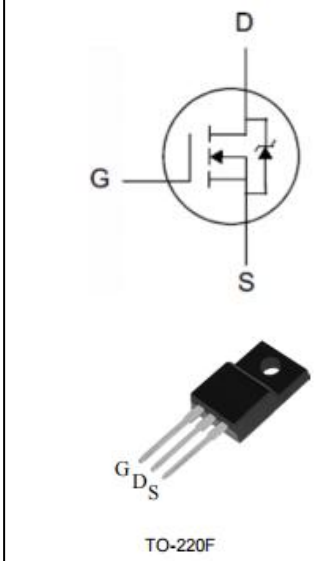
XTMF100N04F

1000V N-ch Planar MOSFET

封装 **Package**



Product Description

BV_{DSS}	1000	V
I_D	4	A
$R_{DS(ON),Typ.}$	2.2	Ω

General Features

- RoHS Compliant
- $R_{DS(ON),typ.}$=2.2Ω@V_{GS}=10V
- Fast Recovery Body Diode
- Low Gate Charge Minimize Switching Loss

Applications

- Adaptor
- Charger
- SMPS Standby Power

Device	Package	Marking
XTMF100N04F	TO-220F	XTMF100N04F

Absolute Maximum Ratings T_j=25℃

Symbol	Parameter	XTMF100N04F	Unit
V_{DSS}	Drain-to-Source Voltage	1000	V
V_{GSS}	Gate-to-Source Voltage	±30	
I_D	Continuous Drain Current	4.0	A
I_{DM}	Pulsed Drain Current at V_{GS}=10V	16	
E_{AS}	Single Pulse Avalanche Energy	450	mJ
P_D	Power Dissipation	33	W
	Derating Factor above 25℃	0.26	W/℃
T_L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300	℃
T_J& T_{STG}	Operating and Storage Temperature Range	-50 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	XTMF100N04F	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	3.78	℃/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	100	℃/W

Electrical Characteristics T_j=25℃

OFF Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
BV_{DSS}	Drain-to-Source Breakdown Voltage	1000	--	--	V	V_{GS}=0V, I_D=250uA
I_{DSS}	Drain-to-Source Leakage Current	--	--	1	uA	V_{DS}=1000V,V_{GS}=0V
		--	--	100		V_{DS}=800V, V_{GS}=0V, T_J =125℃
I_{GSS}	Gate-to-Source Leakage Current	--	--	+100	nA	V_{GS}=+30V, V_{DS}=0V
		--	--	-100		V_{GS}=-30V, V_{DS}=0V

ON Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	2.2	2.5	Ω	V_{GS}=10V, I_D=2A
$V_{GS(TH)}$	Gate Threshold Voltage	3.0	--	5.0	V	V_{DS}=V_{GS} , I_D=250uA
gfs	Forward Transconductance	--	4.5	--	S	V_{DS}=15V,ID=2A

Dynamic Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
C_{iss}	Input Capacitance	--	1470	--	pF	V_{GS}=0V, V_{DS}=25V, f=1.0MHz
C_{rss}	Reverse Transfer Capacitance	--	21	--		
C_{oss}	Output Capacitance	--	115	--		
Q_g	Total Gate Charge	--	36	--	nC	V_{DD}=500V, I_D=4A, V_{GS}=0 to 10V
Q_{gs}	Gate-to-Source Charge	--	7.5	--		
Q_{gd}	Gate-to-Drain (Miller) Charge	--	14	--		

Resistive Switching Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
$td_{(ON)}$	Turn-on Delay Time	--	20	--	ns	V_{DD}=500V, I_D=4A, V_{GS}=10V Rg=4.7Ω
t_{rise}	Rise Time	--	23	--		
$td_{(OFF)}$	Turn-Off Delay Time	--	28	--		
t_{fall}	Fall Time	--	26	--		

Source-Drain Body Diode Characteristics

Symbol	Parameter	Min	Typ	Max	Unit	Test Condition
I_{SD}	Continuous Source Current[1]	--	--	4	A	Integral pn-diode in MOSFET
I_{SM}	Pulsed Source Current[1]	--	--	16		
V_{SD}	Diode Forward Voltage	--	--	1.5	V	I_S=4A, V_{GS}=0V
t_{rr}	Reverse Recovery Time	--	320	--	ns	V_{GS}=0V I_F=IS, di/dt=100A/μs
Q_{rr}	Reverse Recovery Charge	--	1.00	--	uC	

[1] Pulse width≤380μs; duty cycle≤2%

[2] Pulse width≤380μs; duty cycle≤2%.

Typical Characteristics

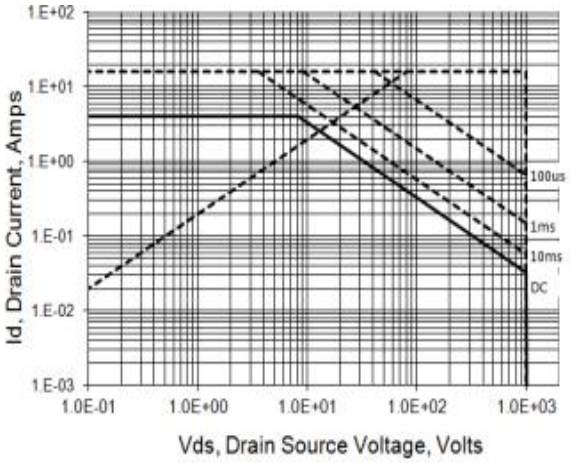


Figure 1 . Maximum Safe Operating Area

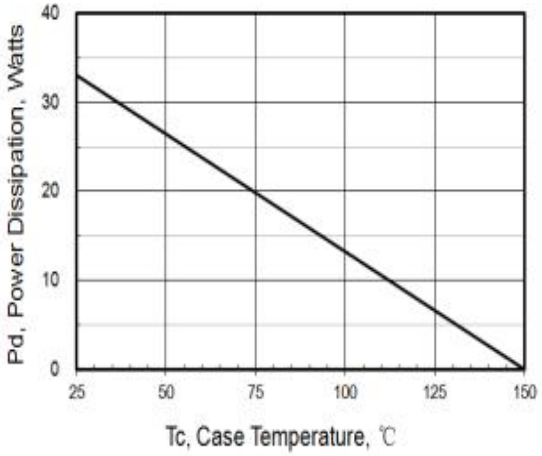


Figure 2 . Maximum Power Dissipation vs Tc

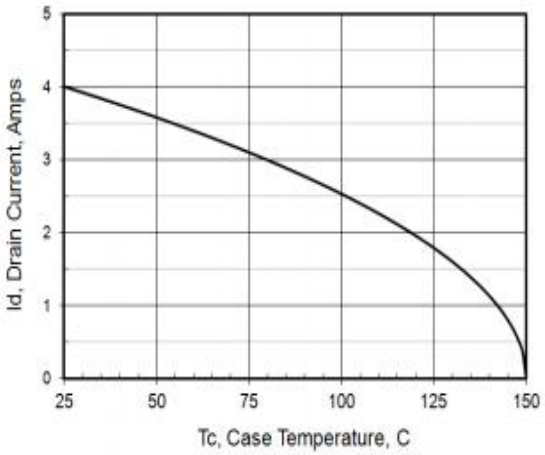


Figure 3 .Id vs Case Temperature

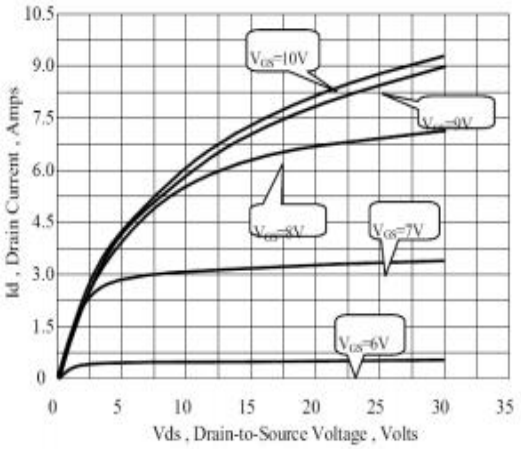


Figure 4 Typical Output Characteristics

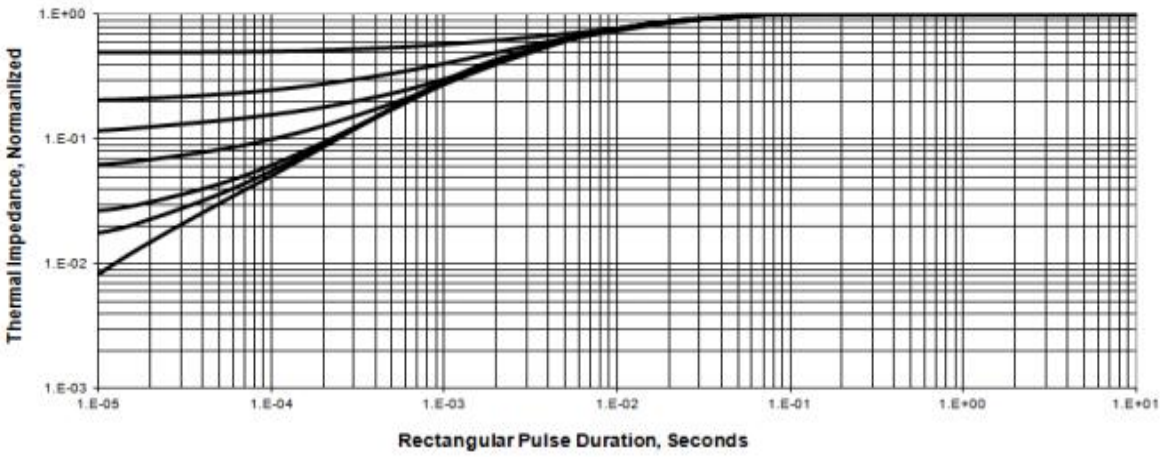


Figure 5. Maximum Transient Thermal Impedance

Typical Characteristics(Cont.)

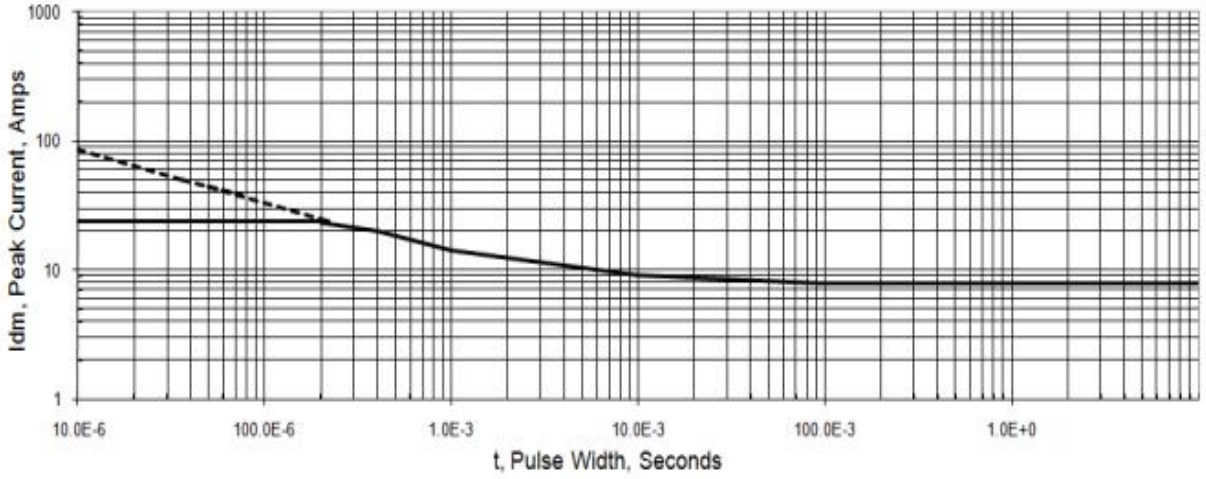


Figure 6. Peak Current Capability

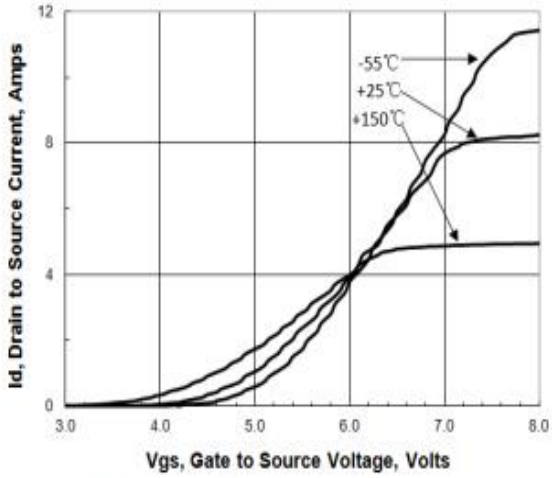


Figure 7. Transfer Characteristics

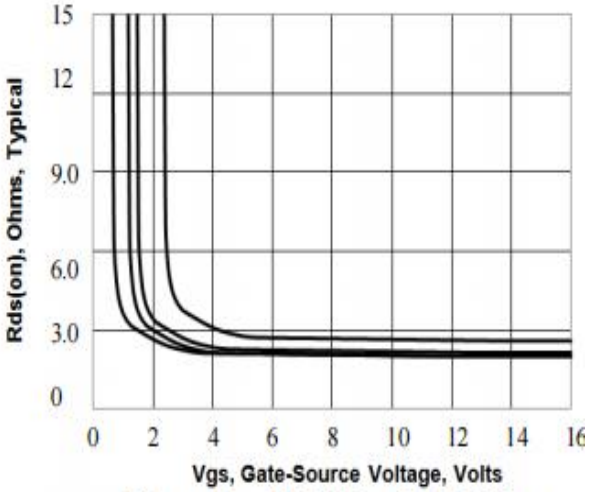


Figure 5. RDSONvs Gate Voltage

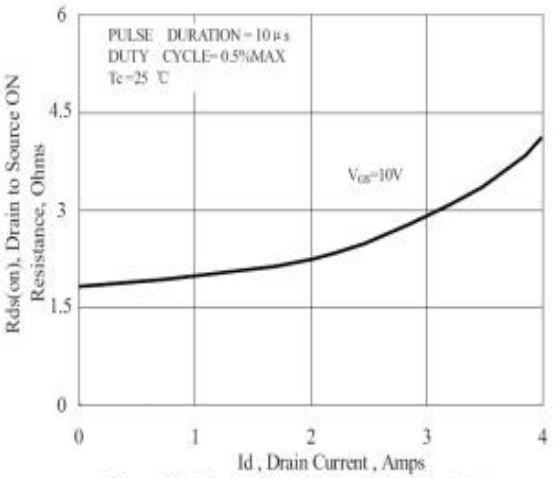


Figure 9 Typical Drain to Source ON Resistance vs Drain Current

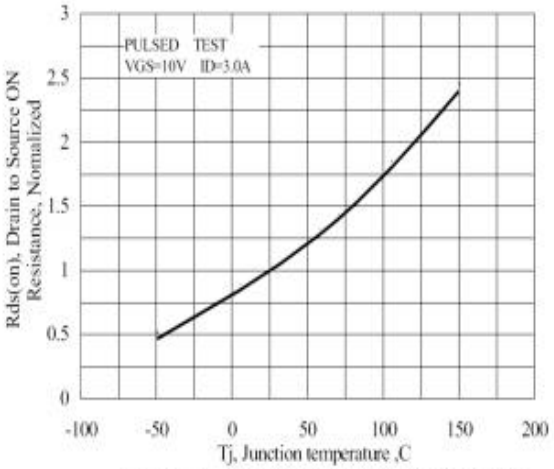


Figure 10 Typical Drian to Source on Resistance vs Junction Temperature

Typical Characteristics(Cont.)

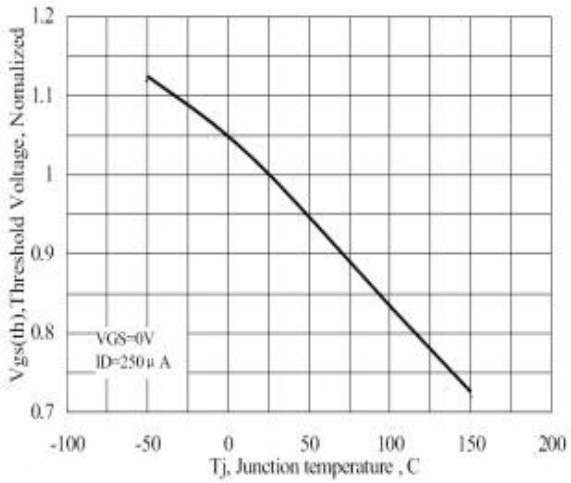


Figure 11 Typical Theshold Voltage vs Junction Temperature

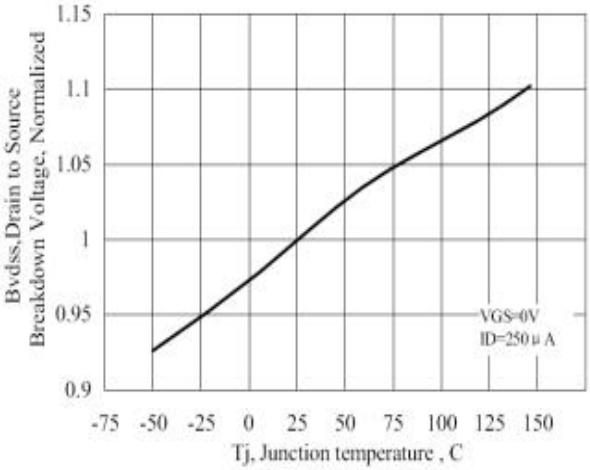


Figure 12 Typical Breakdown Voltage vs Junction Temperature

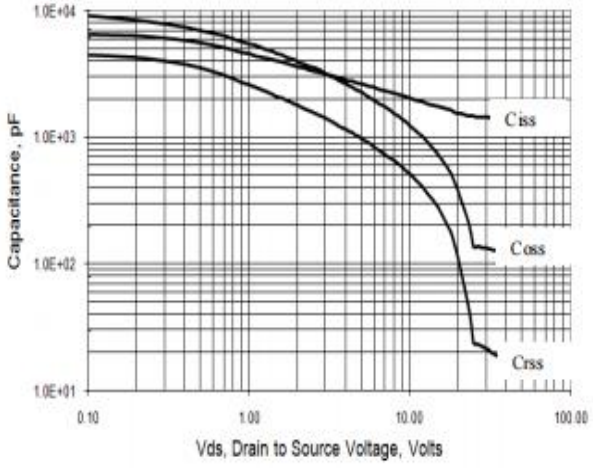


Figure 13. Capacitance vs Vds

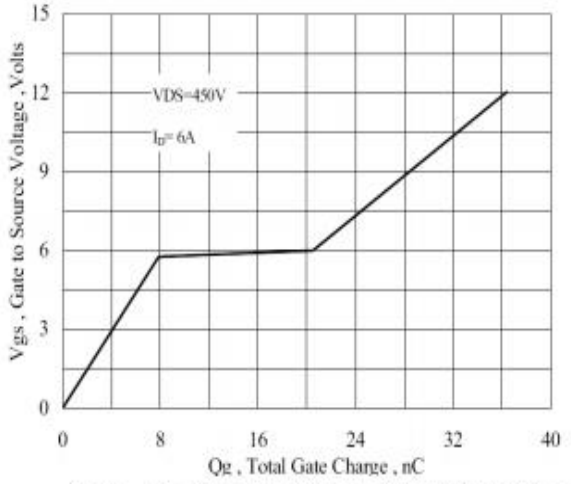


Figure 14 Typical Gate Charge vs Gate to Source Voltage

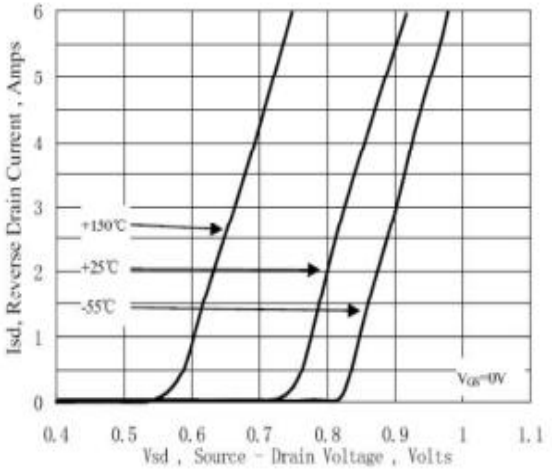


Figure 15 Typical Body Diode Transfer Characteristics

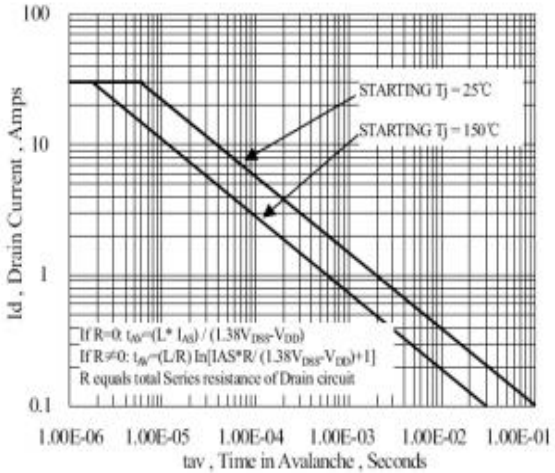


Figure 16 Unclamped Inductive Switching Capability

Test Circuits and Waveforms

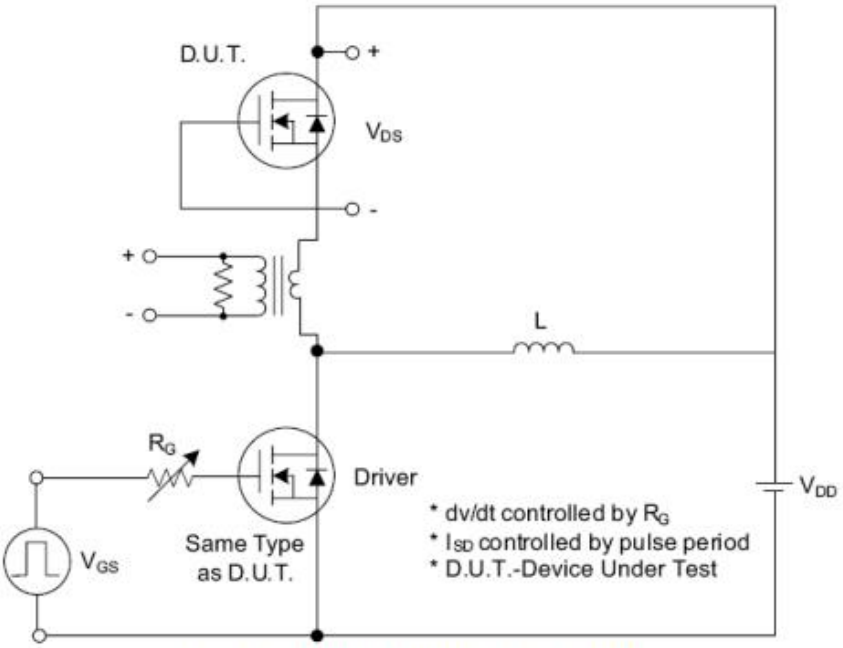


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

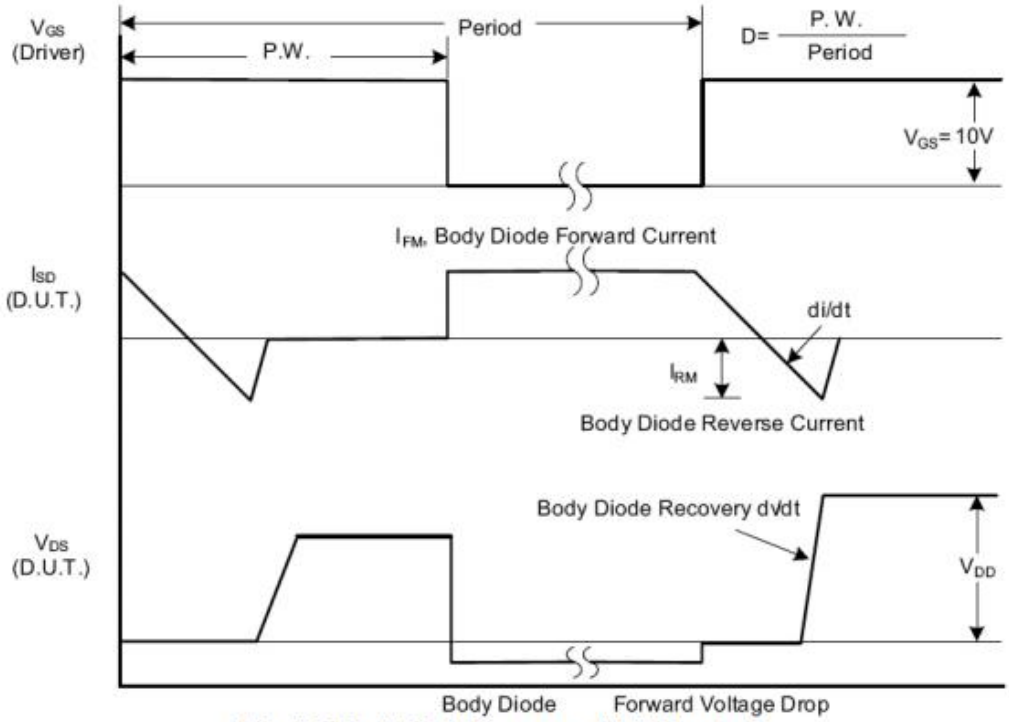


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

Test Circuits and Waveforms (Cont.)

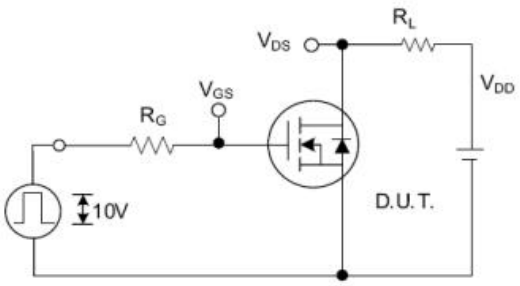


Fig. 2.1 Switching Test Circuit

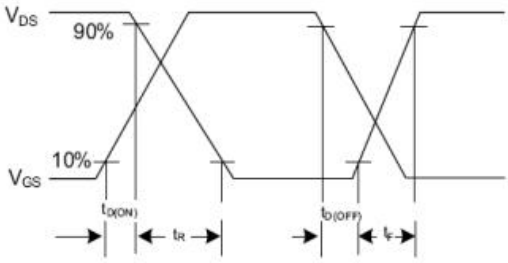


Fig. 2.2 Switching Waveforms

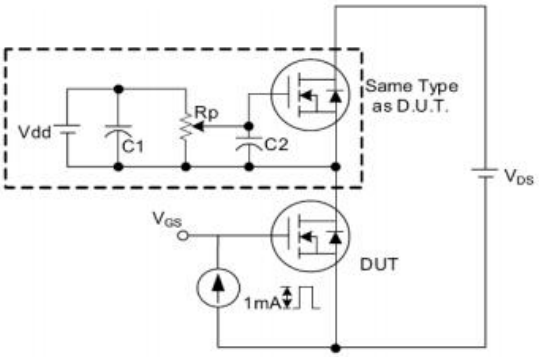


Fig. 3 . 1 Gate Charge Test Circuit

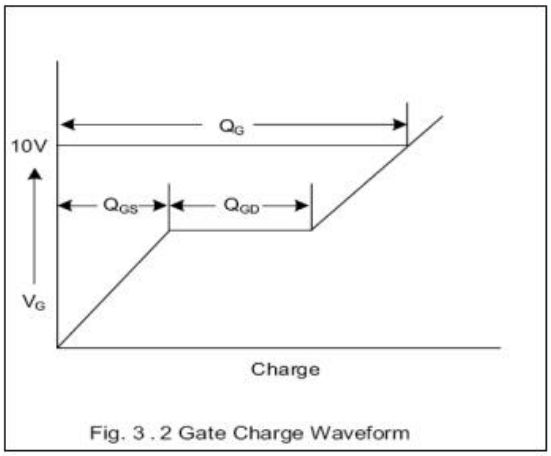


Fig. 3 . 2 Gate Charge Waveform

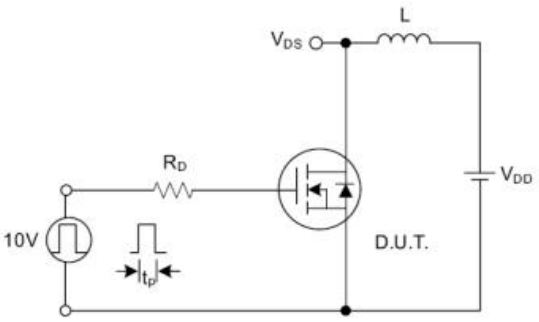


Fig. 4.1 Unclamped Inductive Switching Test Circuit

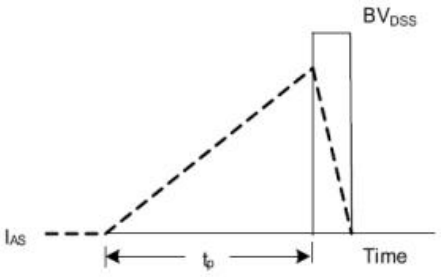


Fig. 4.2 Unclamped Inductive Switching Waveforms